

H5N2515P-VB Datasheet

N-Channel 250 V (D-S) 175 °C MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	$\mathbf{R}_{DS(on)}$ (Ω) \mathbf{I}_{D} (A)		Q _g (Typ)	
250	0.040 at V _{GS} = 10 V	60	95	
250	0.045 at V _{GS} = 6 V	55	90	

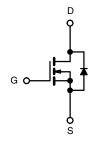
FEATURES

- Trench Power MOSFETS
- 175 °C Junction Temperature
- New Low Thermal Resistance Package
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

Industrial





N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	S (T _C = 25 °C, unless oth	nerwise noted)			
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	250	V	
Gate-Source Voltage		V _{GS}	± 30	V	
Continuous Drain Current ($T_J = 175 \ ^{\circ}C$)	T _C = 25 °C	1-	60	А	
	T _C = 125 °C	I _D	35		
Pulsed Drain Current		I _{DM}	200		
Avalanche Current		I _{AR}	35		
Repetitive Avalanche Energy ^a	L = 0.1 mH	E _{AR}	61	mJ	
Maximum Power Dissipation ^a	T _C = 25 °C	P	300 ^b	w	
	T _A = 25 °C ^c	– P _D –	3.75		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Limit	Unit	
Junction-to-Ambient (PCB Mount) ^c	R _{thJA}	40	°C/W	
Junction-to-Case (Drain)	R _{thJC}	0.5		

Notes:

a. Duty cycle \leq 1 %.

b. See SOA curve for voltage derating.

c. When mounted on 1" square PCB (FR-4 material).

Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit
Static				1		
Drain-Source Breakdown Voltage	V _{DS}	$V_{DS} = 0 V, I_{D} = 250 \mu A$	250			v
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2		4	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 30 V$			± 250	nA
Zero Gate Voltage Drain Current		$V_{DS} = 250 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μΑ
	I _{DSS}	V_{DS} = 250 V, V_{GS} = 0 V, T_{J} = 125 °C			50	
		V_{DS} = 250 V, V_{GS} = 0 V, T_{J} = 175 °C			250	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	70			А
		V _{GS} = 10 V, I _D = 30 A		0.040		- Ω
Drain-Source On-State Resistance ^a	P	V_{GS} = 10 V, I _D = 30 A, T _J = 125 °C		0.091		
	R _{DS(on)}	V_{GS} = 10 V, I _D = 30 A, T _J = 175 °C		0.123		
		V _{GS} = 6 V, I _D = 25 A		0.045		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		70		S
Dynamic ^b	4			+		
Input Capacitance	C _{iss}			5000		pF
Output Capacitance	C _{oss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		300		
Reverse Transfer Capacitance	C _{rss}			170		
Total Gate Charge ^c	Qg			95	140	nC
Gate-Source Charge ^c	Q _{gs}	V_{DS} = 125 V, V_{GS} = 10 V, I_{D} = 45 A		28		
Gate-Drain Charge ^c	Q _{gd}			34		
Gate Resistance	R _g	f = 1 MHz		1.6		Ω
Turn-On Delay Time ^c	t _{d(on)}			22	35	
Rise Time ^c	t _r	V_{DD} = 100 V, R _L = 2.78 Ω I _D \cong 45 A, V _{GEN} = 10 V, R _g = 2.5 Ω		220	330	ns
Turn-Off Delay Time ^c	t _{d(off)}			40	60	
Fall Time ^c	t _f			145	220	
Source-Drain Diode Ratings and Cha	aracteristics (T _C = 25 °C) ^b		•		
Continuous Current	۱ _S				45	А
Pulsed Current	I _{SM}				70	A
Forward Voltage ^a	V _{SD}	I _F = 45 A, V _{GS} = 0 V		1	1.5	V
Reverse Recovery Time	t _{rr}	I _F = 45 A, di/dt = 100 A/μs		150	225	ns
Peak Reverse Recovery Current	I _{RM(REC)}			12	18	Α
Reverse Recovery Charge	Q _{rr}			0.9	2	μC

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

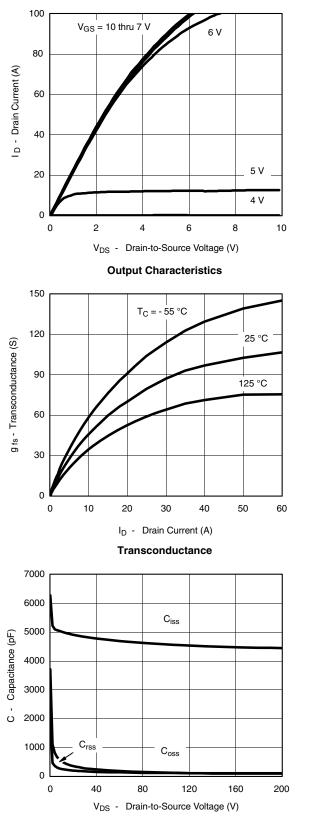
b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

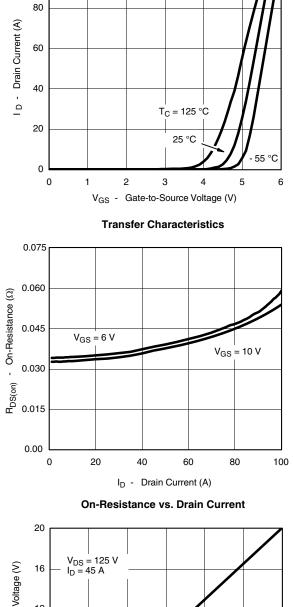
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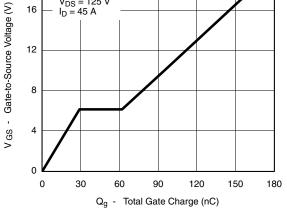


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





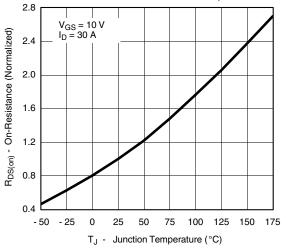
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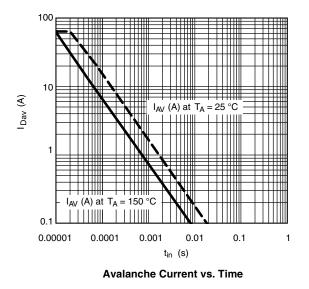
Gate Charge

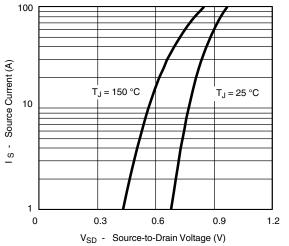




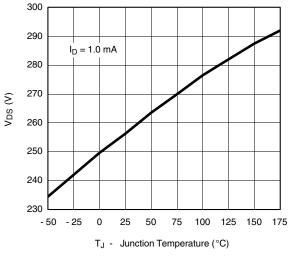


On-Resistance vs. Junction Temperature





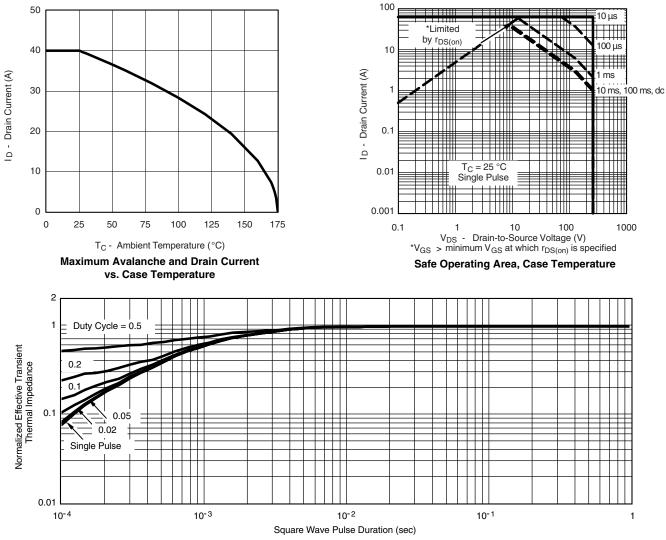
Source-Drain Diode Forward Voltage



Drain Source Breakdown vs. Junction Temperature



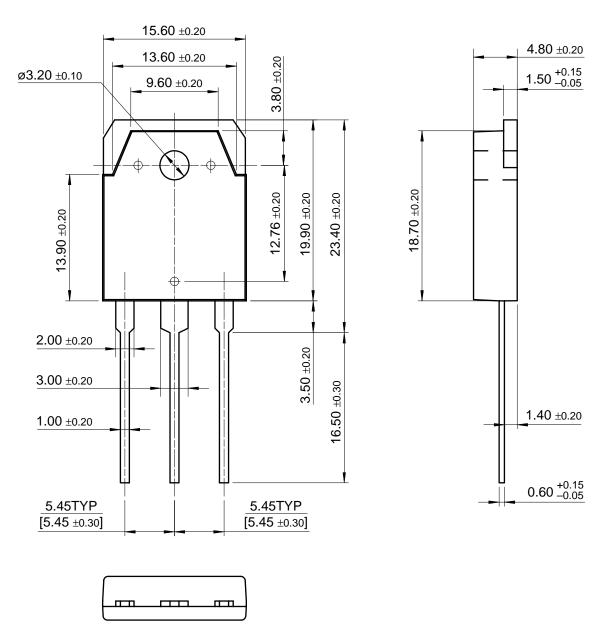
THERMAL RATINGS



Normalized Thermal Transient Impedance, Junction-to-Case



TO-3P





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